

Notice of References Cited	Application/Control No. 09/811,904	Applicant(s)/Patent Under Reexamination TORTI ET AL.	
	Examiner Zia R. Hashmi	Art Unit 2881	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,767,511 ✓	06-1998	Macler, Michel	250/281
	B	US-6,278,111 ✓	08-2001	Sheehan et al.	250/288
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	R					
	S					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
✓	U	Mack et al. "Gas Cluster Ion Beam Size Diagnostics and Workpiece Processing", pub. no: US/2002/0070361 A1, published June 13, 2002.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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